Sheet	1	of	2	
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		US Dept. of Cor PATENT & TRADEMARK C			ATTY DOCKET NO. 126213		APPLICATION NO. 10/559,775		
INFORMATION DISCLOSURE STATEMENT									
(Use several sheets if necessary)			APPLICANTS Lambertus MEULENBRUGGE et al.						
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Examiner Initials	Cite No.	Document Number	Date		*	Name			
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Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance									
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Date: March 22, 2006

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 126213		APPLICATION NO. 10/559,775				
INFORMATION DISCLOSURE STATEMENT										
(Use several sheets if necessary)				APPLICANTS Lambertus MEULENBRUGGE et al.			<u> </u>			
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